

Notice of References Cited	Application/Control No. 10/822,023		Applicant(s)/Patent Under Reexamination CHURT ET AL.	
	Examiner David Q. Nguyen		Art Unit 2617	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0030368	02-2008	Kagan, Erran	340/870.02
*	B	US-6,195,018	02-2001	Ragle et al.	340/870.01
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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